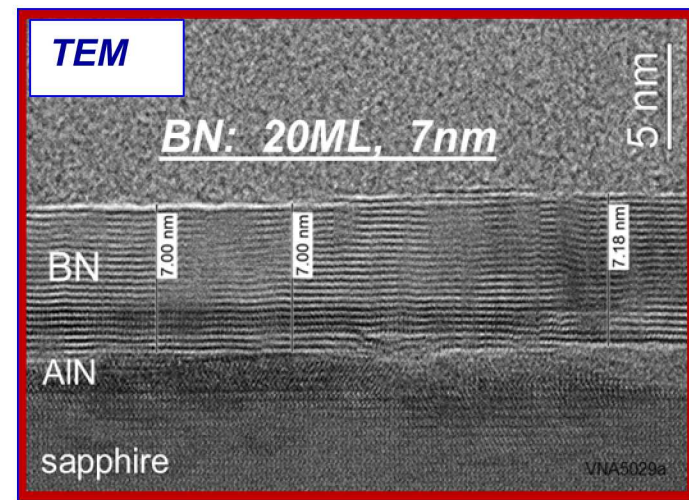
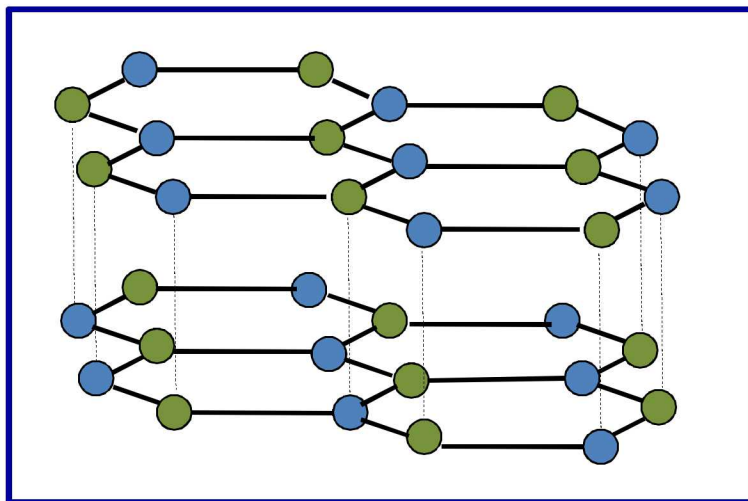


Growth of hBN by High-Temperature Metal-organic Chemical Vapor Deposition

A. Rice, M. Crawford, A. Allerman, & P. Sharps

Sandia National Laboratories, Albuquerque, NM 87185



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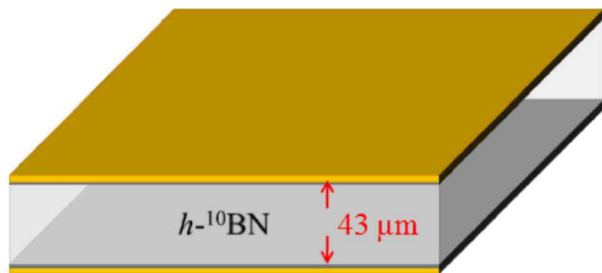
Background - Why hBN?

2D applications

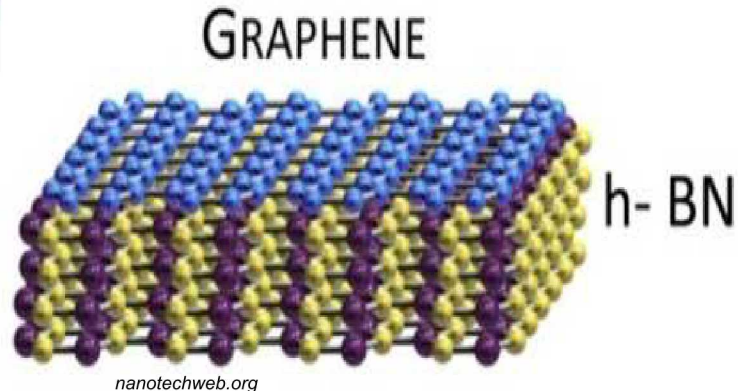
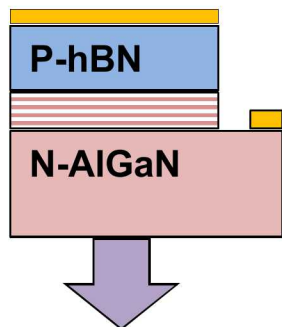
- Dielectric substrate for high mobility graphene
- Stacked monolayers w/graphene a “circuit board” for TMDs
- Encapsulant for quantum Hall devices
- Single photon emitters, gas sensing, hyperbolic optics

Bulk applications

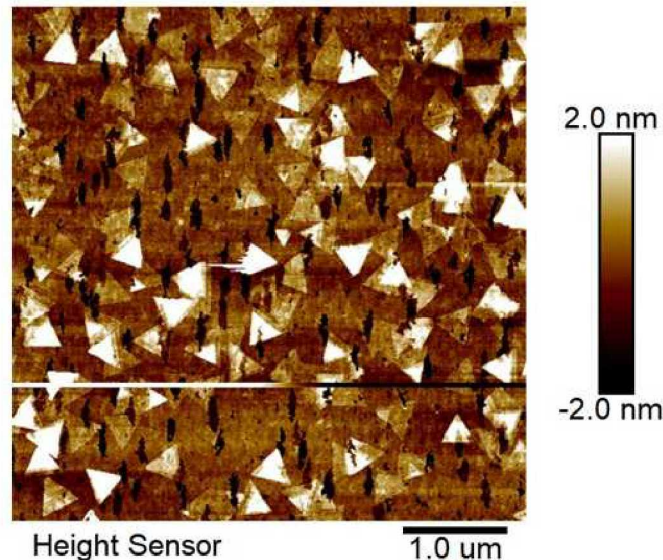
- Thermal neutron detection
- UV optoelectronics



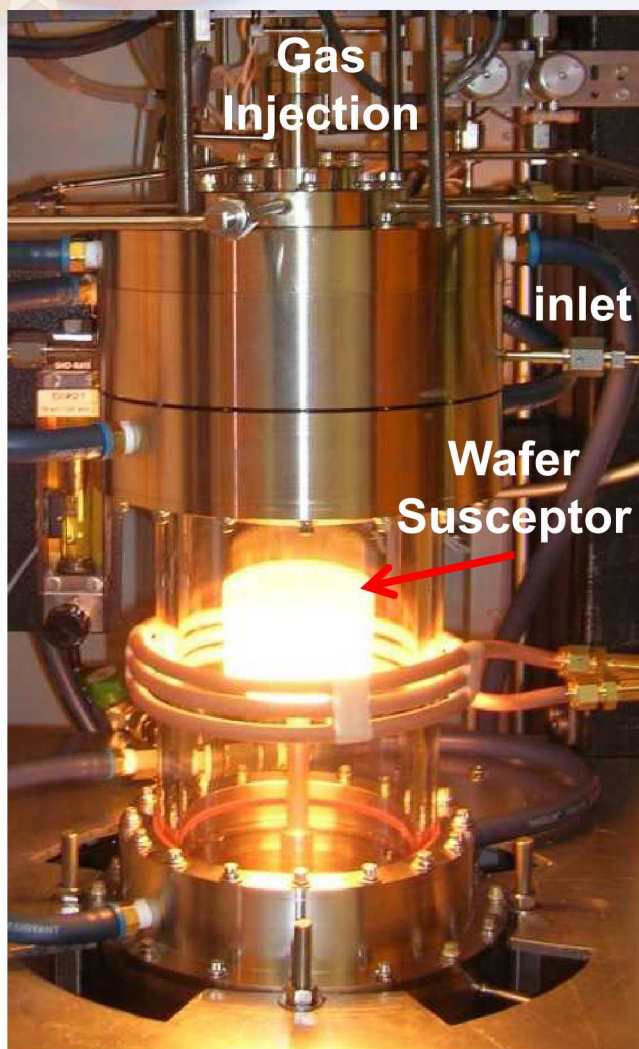
Maity et al., 2016



Mono- and multi-layer WSe_2 grown on hBN



High Temperature MOCVD System



- Advantages of HT growth

- Cold walled, RF heated up to 1900°C
- Increased surface mobility of Group-III atoms

- Continuous Growth (TEB + NH₃)

- Temperature: 1200 – 1600 - 1800°C
- Pressure: 50 torr
- NH₃: 0.1 – 2 - 5 slpm
- TEB: 12 μmoles/min
- Carrier gas: N₂ Diluent gas: H₂

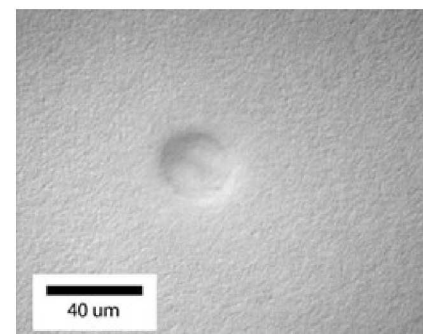
- Continuous Growth (Borazine)

- Temperature: 1300 – 1600 - 1700°C
- Pressure: 50 torr
- Borazine: 0.06 – 3.6 μmoles/min
- Carrier & diluent gas: N₂

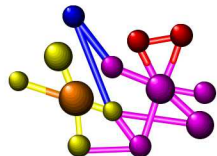
- Substrates

- Sapphire & SiC

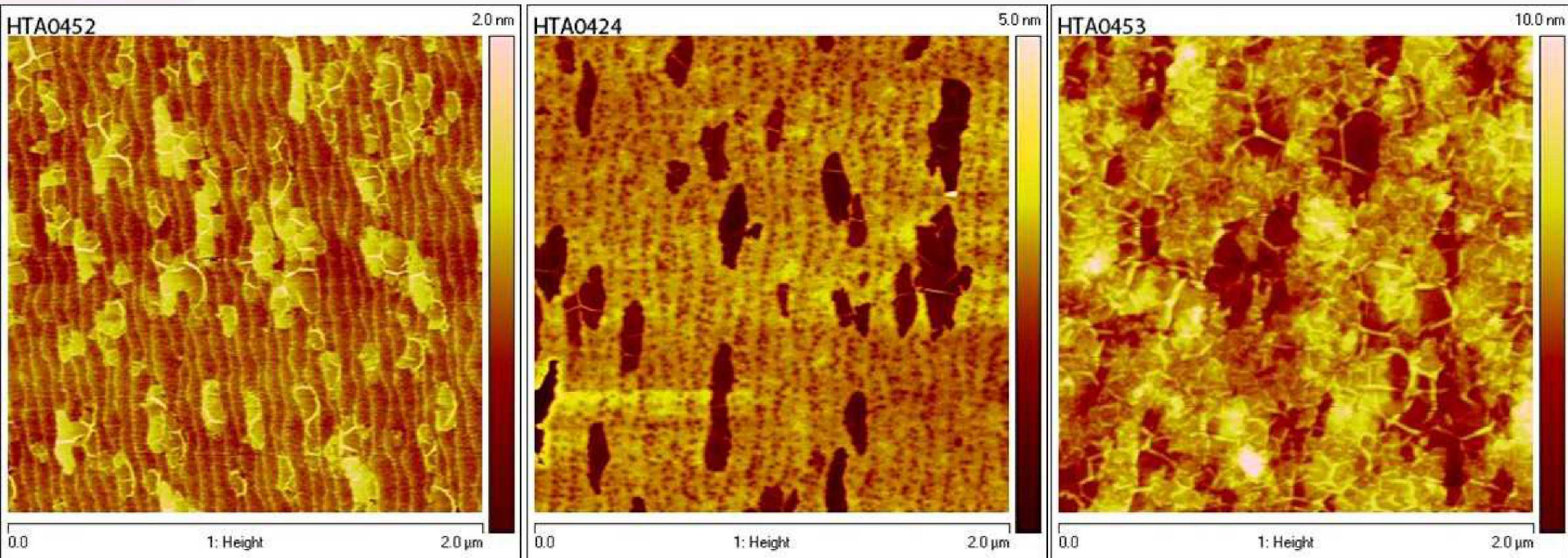
40 mm thick visibly transparent hBN film on SiC substrate w/defect



Reactor Design from Prof. Zlatko Sitar (NC State)



hBN Monolayer Growth

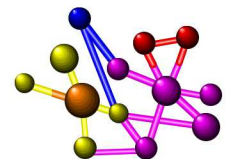


<1 monolayer
RMS roughness ~0.2 nm

1 to 3 monolayers
RMS roughness ~0.5 nm

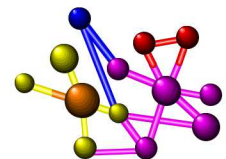
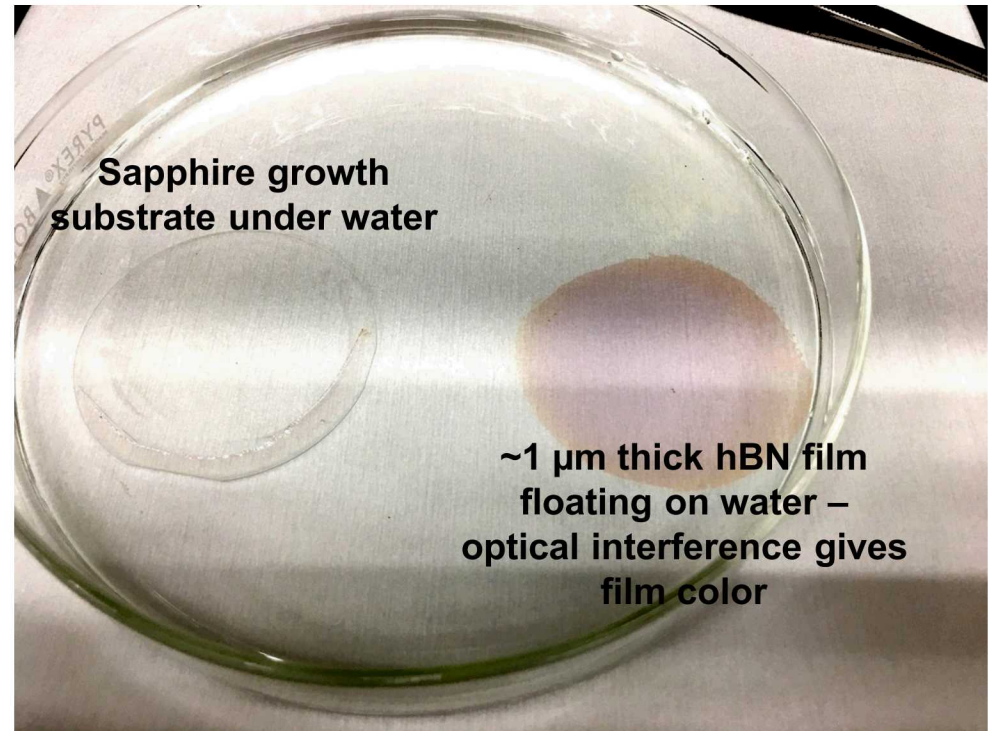
>3 monolayers
RMS roughness >1 nm

- Have developed FTIR differential reflectance technique with better than 1 monolayer thickness resolution



Separating hBN From Sapphire

- Transfer hBN to other materials
- Allow for backside contacts
- Flatten surface, reduce strain
- Works with DI water, requires scribe at edge, “wrinkled” film, & near instantaneous lift of for 2” wafer
- Does not work with IPA – film tears apart, curls up, & stays submerged



n Detector – Fabrication & Integration

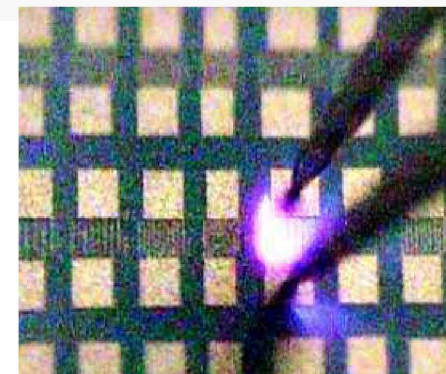
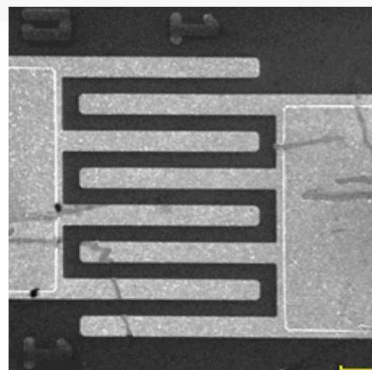
Initial test structures:

- MSM design with bulk samples and interdigitated front contacts with 2, 5, 10, 15 μm gaps
- Characterized by photocurrent and ion beam induced current (IBIC) w/100 keV Li^+
- Difficult to extract $\mu\tau$ data due to non-uniform electric fields
- Analysis suggests surface leakage

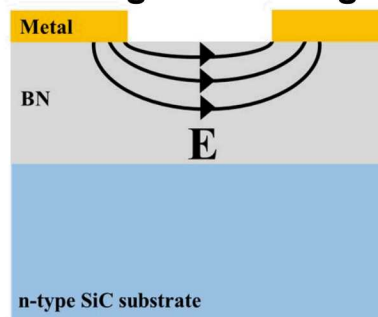
Revised design:

- Parallel plate, vertical structure to reduce $\mu\tau$ analysis complexity
- Probe volume of thicker films
- Side injected IBIC to probe thick film volumes

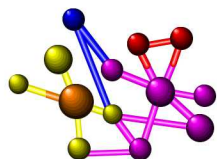
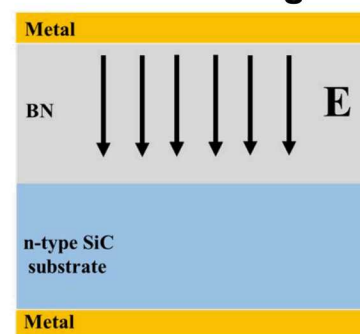
Interdigitated Design



E-field for Interdigitated Design



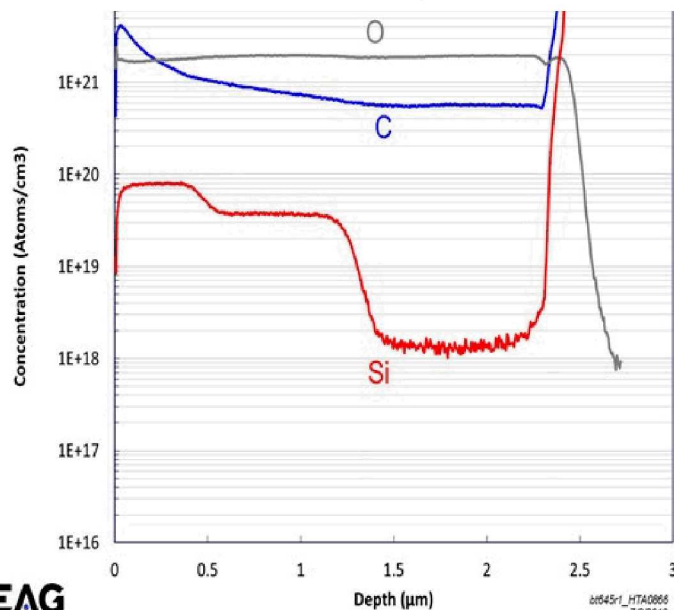
E-field for Vertical Design



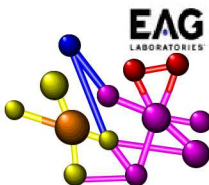
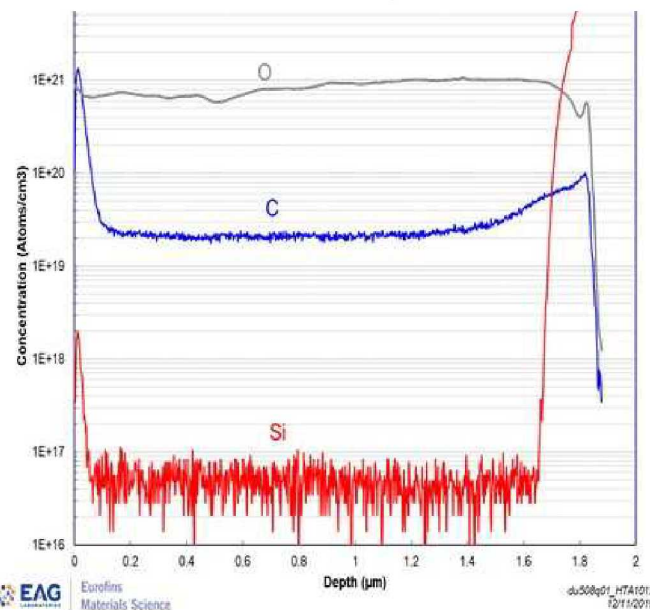
hBN Material Characterization

- SIMS analysis of hBN material indicates challenge
- Growth w/TEB & NH_3 (w/Si) has high C & O, consistent w/other results
- Borazine, w/no C, has reduced C but still too high
- Continuing to work for a reduction in C & O (e.g., higher purity precursors, alternate growth method)

Growth w/TEB [$(\text{C}_2\text{H}_5)_3\text{B}$] & NH_3 , w/Si doping



Growth w/Borazine ($\text{B}_3\text{H}_6\text{N}_3$), no Si doping



Summary

- Both monolayer and bulk hBN (40 μm) epitaxial layers demonstrated
- Demonstrated ability to remove hBN layers from sapphire
- Grown, fabricated, and tested bulk hBN for neutron testing
- Vertical, parallel plate structure preferred due to uniform E-field and avoidance of surface issues
- C and O challenges with either TEB/ NH_3 and borazine precursors
- Continuing work to reduce impurities in the film growth

Funding Acknowledgement: This work was funded by Sandia's Laboratory Directed Research and Development Program

